

## -55V P-Channel Enhancement Mode MOSFET

### Description

The AP4P05MI uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = -55V$   $I_D = -4.2A$

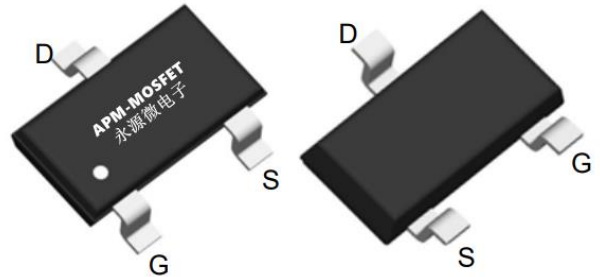
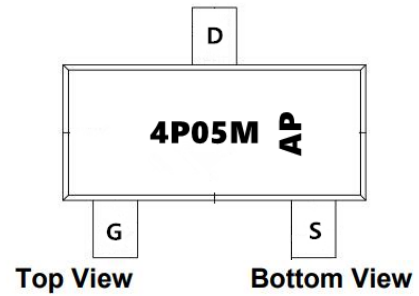
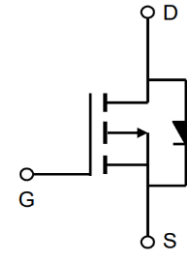
$R_{DS(ON)} < 125m\Omega$  @  $V_{GS} = -10V$  (Type: 108m $\Omega$ )

### Application

Battery protection

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP4P05MI	SOT23-3L	4P05M-AP	3000

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	-55	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
$I_D@T_A=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ -10V^1$	-4.2	A
$I_D@T_A=70^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ -10V^1$	-2.4	A
IDM	Pulsed Drain Current <sup>2</sup>	-16	A
$P_D@T_A=25^\circ\text{C}$	Total Power Dissipation <sup>3</sup>	1	W
TSTG	Storage Temperature Range	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup>	125	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>	80	°C/W

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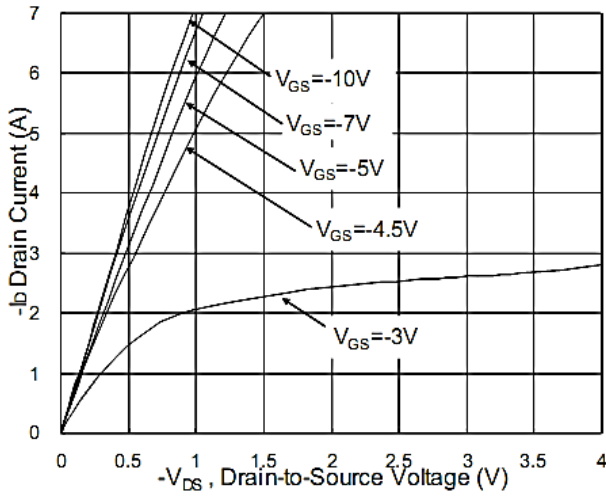
### Electrical Characteristics (TC=25 °C unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-55	-58	---	V
$\Delta BVDSS/\Delta T_J$	$BV_{DSS}$ Temperature Coefficient	Reference to 25°C, $I_D=-1mA$	---	-0.021	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=-10V, I_D=-1.5A$	---	108	125	mΩ
		$V_{GS}=-4.5V, I_D=-1A$	---	125	155	mΩ
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=-250\mu A$	-1.0	1.6	-2.5	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	4.08	---	mV/°C
IDSS	Drain-Source Leakage Current	$V_{DS}=-48V, V_{GS}=0V, T_J=25^\circ C$	---	---	1	uA
IDSS		$V_{DS}=-48V, V_{GS}=0V, T_J=55^\circ C$	---	---	5	
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	±100	nA
gfs	Forward Transconductance	$V_{DS}=-5V, I_D=-1.5A$	---	5.9	---	S
Qg	Total Gate Charge (-4.5V)	$V_{DS}=-20V, V_{GS}=-4.5V, I_D=-1.5A$	---	4.6	---	nC
Qgs	Gate-Source Charge		---	1.4	---	nC
Qgd	Gate-Drain Charge		---	1.62	---	nC
Td(on)	Turn-On Delay Time	$V_{DS}=-15V, V_{GS}=-10V, R_G=3.3\Omega, I_D=-1A$	---	17.4	---	ns
Tr	Rise Time		---	5.4	---	ns
Td(off)	Turn-Off Delay Time		---	37.2	---	ns
Tf	Fall Time		---	2.4	---	ns
Ciss	Input Capacitance	$V_{DS}=-15V, V_{GS}=0V, f=1MHz$	---	531	---	pF
Coss	Output Capacitance		---	59	---	pF
Crss	Reverse Transfer Capacitance		---	38	---	pF
IS	Continuous Source Current <sup>1,4</sup>	$V_G=V_D=0V, \text{Force Current}$	---	---	-1.7	A
ISM	Pulsed Source Current <sup>2,4</sup>		---	---	-7	A
VSD	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0V, I_S=-1A, T_J=25^\circ C$	---	---	-1.2	V

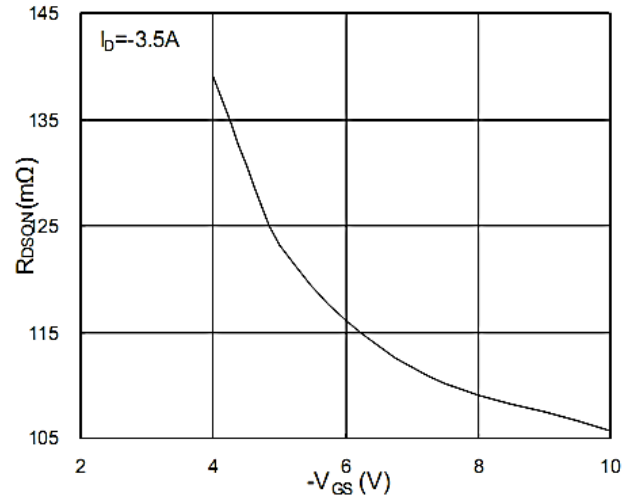
Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width  $\cong 300\mu s$  , duty cycle  $\cong 2\%$
- 3、The power dissipation is limited by 150°C junction temperature
- 4、The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.

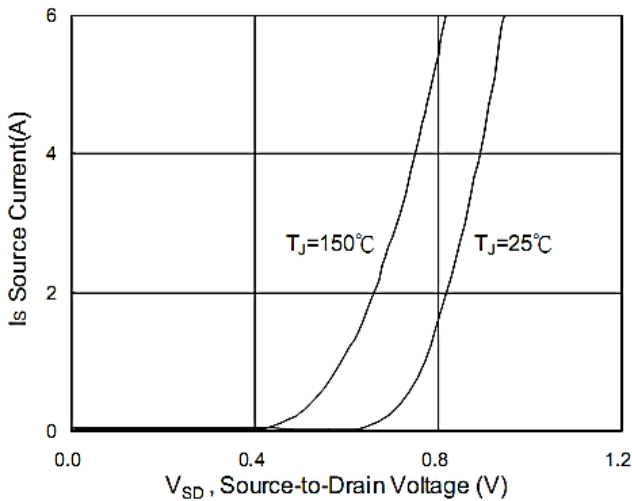
**Typical Characteristics**



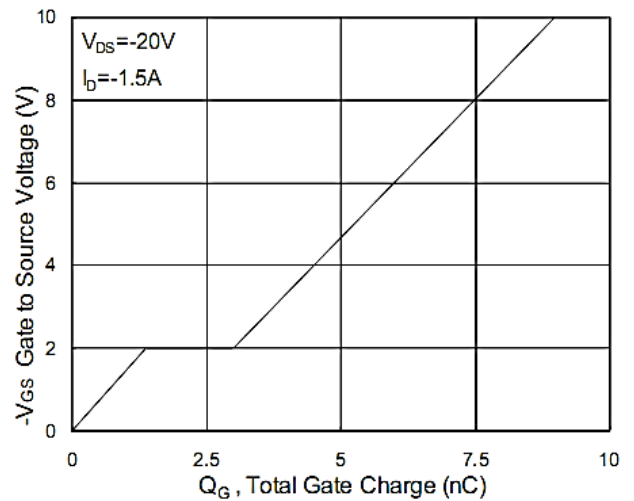
**Fig.1 Typical Output Characteristics**



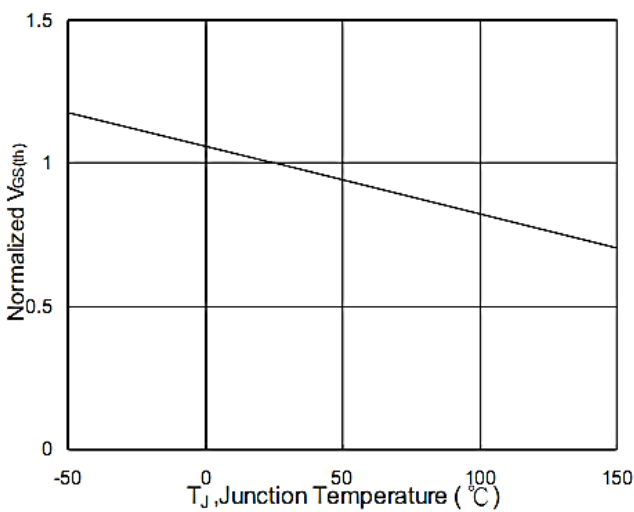
**Fig.2 On-Resistance v.s Gate-Source**



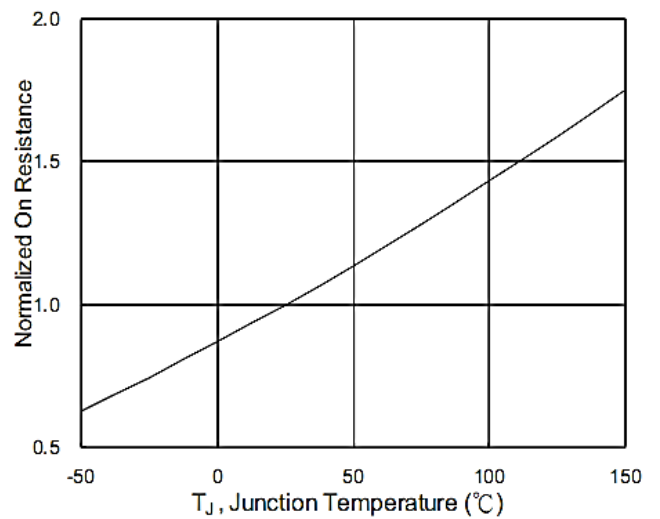
**Fig.3 Forward Characteristics Of Reverse**



**Fig.4 Gate-Charge Characteristics**



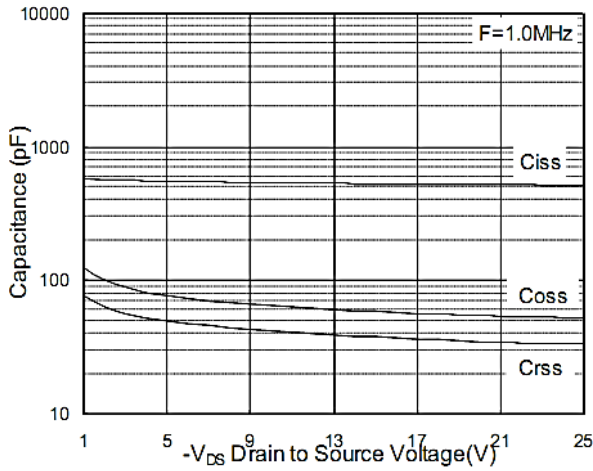
**Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$**



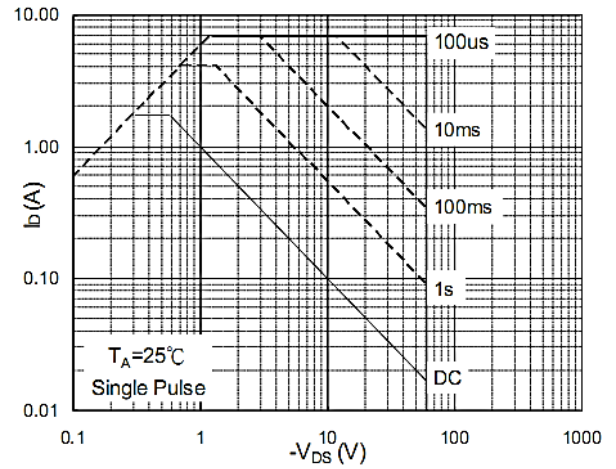
**Fig.6 Normalized  $R_{DS(on)}$  v.s  $T_J$**



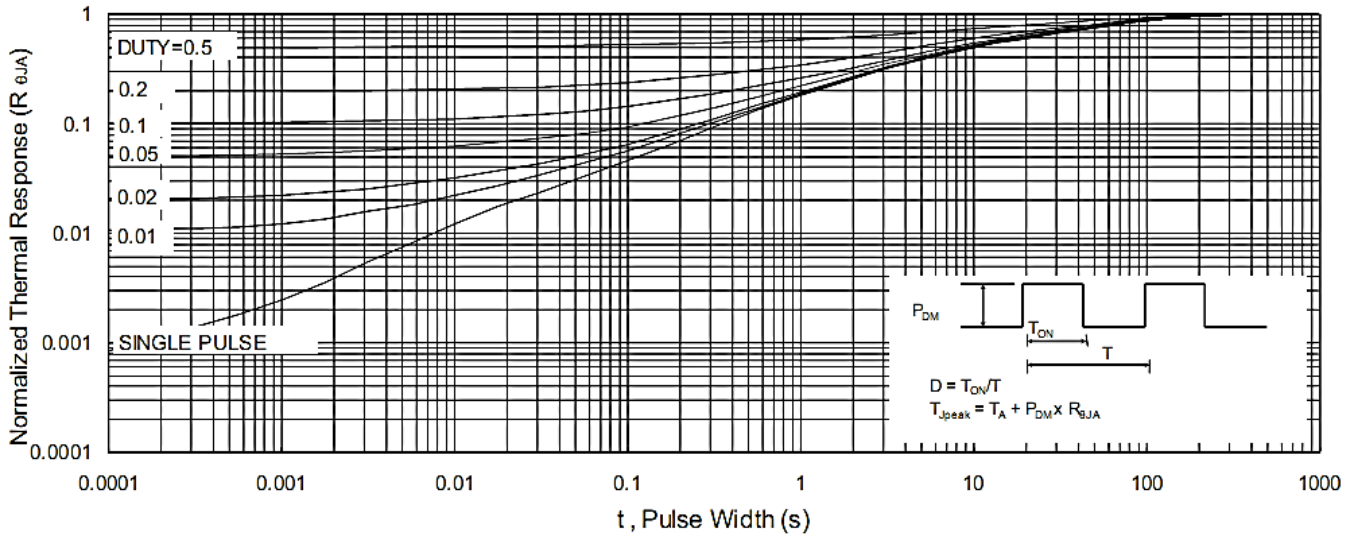
**-55V P-Channel Enhancement Mode MOSFET**



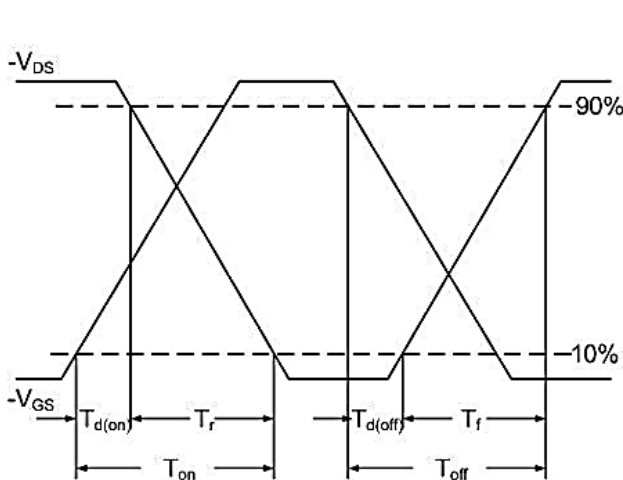
**Fig.7 Capacitance**



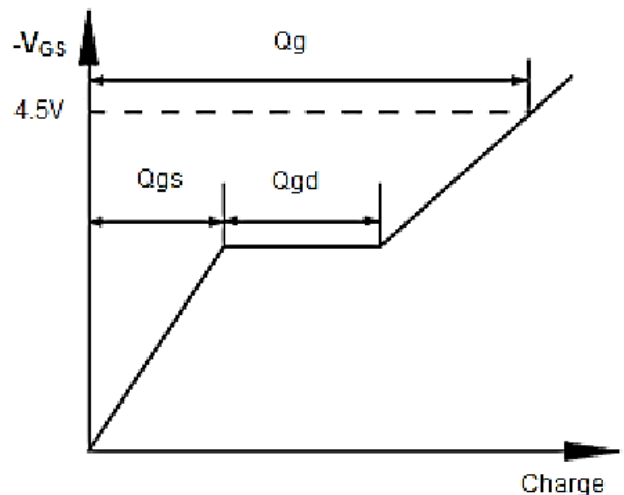
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**

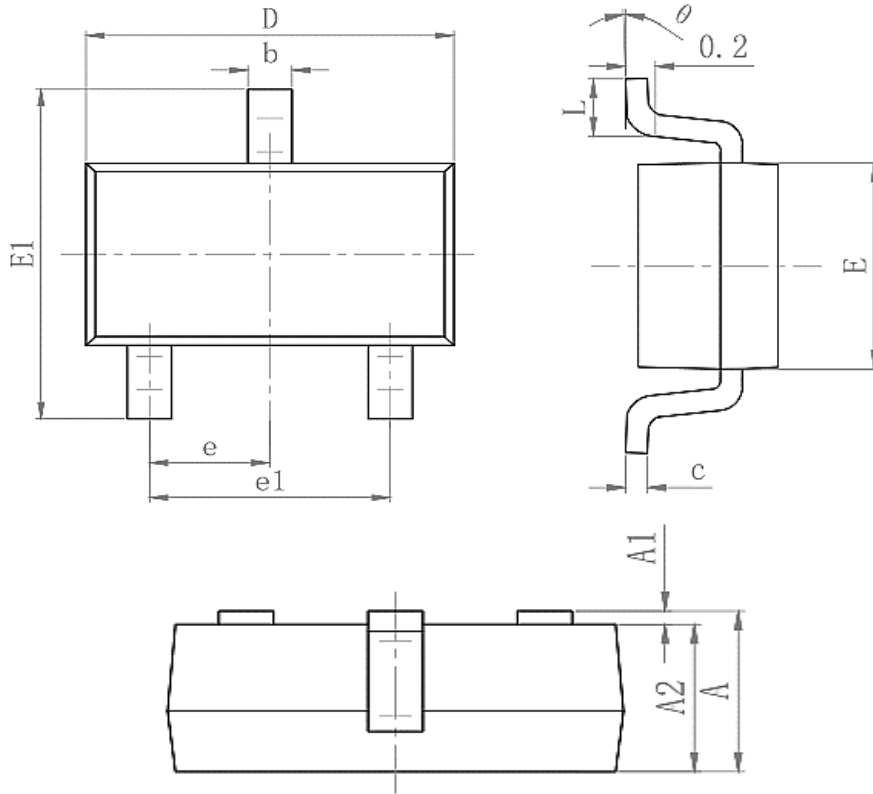


**Fig.10 Switching time waveform**



**Fig.11 Gate Charge waveform**

### Package Mechanical Data-SOT23-3-XC-Single



Symbol	Dimensions In Millimeters	
	Min.	Max.
A	1.050	1.250
A1	0.000	0.100
A2	1.050	1.150
b	0.25	0.45
c	0.100	0.200
D	2.820	3.020
E	1.5	1.7
E1	2.650	2.950
e	0.950(BSC)	
e1	1.800	2.000
L	0.300	0.500
$\theta$	0°	8°

**-55V P-Channel Enhancement Mode MOSFET****Attention**

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Edition	Date	Change
Rve1.0	2021/4/13	Initial release

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